

Application/Control No.	Applicant(s)/Patent under Reexamination
10/721,875	ENDO ET AL.
Examiner	Art Unit
ALEX LIEW	2624

	SEARCHED				
Class	Subclass	Date	Examiner		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
Interference search		3/12/2008	AL		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
382/106,154 limited to text search	4/23/2007	AL
348/36-39 limited to text search	4/23/2007	AL
382/274 limited to text search	4/25/2007	AL
382/106,154 limited to text search 382 limited to text search 348/36-39 limites to text search	12/21/2007	AL
382/106,154 limited to text search 382 limited to text search 348/36-39 limites to text search	3/12/2008	AL
Inventor name search	3/12/2008	AL